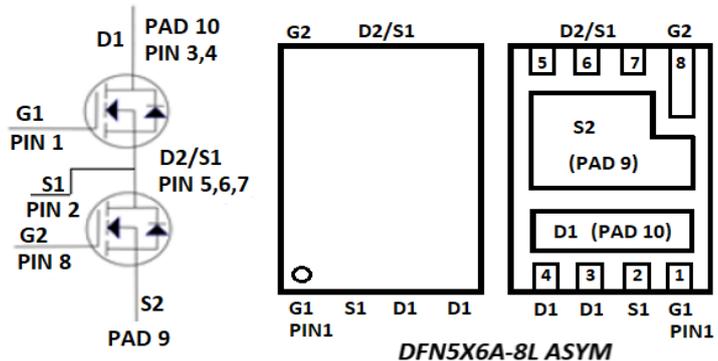


Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor

▪Product Summary:

	Q1	Q2
$BV_{DSS}$	30V	30V
$R_{DS(ON)(MAX.)}@V_{GS}=10V$	4.3mΩ	0.95mΩ
$R_{DS(ON)(MAX.)}@V_{GS}=4.5V$	7.0mΩ	1.15mΩ
$I_D @T_C=25^{\circ}C$	86A	240A
$I_D @T_A=25^{\circ}C$	21A	44A

▪ Pin Description:



Dual N Channel MOSFET

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant



▪ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^{\circ}C$  Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS		UNIT	
		Q1	Q2		
Gate-Source Voltage	$V_{GS}$	20/-16	±12	V	
Continuous Drain Current	$I_D$	$T_C = 25^{\circ}C$	86	240	A
		$T_C = 100^{\circ}C$	54	151	
Continuous Drain Current	$I_D$	$T_A = 25^{\circ}C$	21	44	
		$T_A = 70^{\circ}C$	17	35	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	170	699		
Avalanche Current	$I_{AS}$	70	120		
Avalanche Energy	L = 0.01mH	EAS	24.5	72	
Repetitive Avalanche Energy <sup>2</sup>	L = 0.05mH	EAR	122.5	360	
Power Dissipation	$P_D$	$T_C = 25^{\circ}C$	50	89.3	W
		$T_C = 100^{\circ}C$	20	35.7	
Power Dissipation	$P_D$	$T_A = 25^{\circ}C$	3.1	3.1	W
		$T_A = 70^{\circ}C$	2	2	
Operating Junction & Storage Temperature Range	$T_{jv}, T_{stg}$	-55 to 150		°C	

▪ 100% UIS testing in condition of  $V_D=25V, L=0.01mH, V_G=10V, I_L=42A, R_G=25\Omega$ , Rated  $V_{DS}=30V$  N-CH\_Q1

▪ 100% UIS testing in condition of  $V_D=25V, L=0.01mH, V_G=10V, I_L=72A, R_G=25\Omega$ , Rated  $V_{DS}=30V$  N-CH\_Q2

▪THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM		UNIT
			Q1	Q2	
Junction-to-Case	$R_{\theta JC}$		2.5	1.4	°C/W
Junction-to-Ambient <sup>3</sup>	$t \leq 10s$	$R_{\theta JA}$	40	40	
	Steady-State	$R_{\theta JA}$	65	65	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle < 1%

<sup>3</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^{\circ}C$ .

<sup>4</sup>Guarantee by Engineering test



▪ Q1\_ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage <sup>4</sup>	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30			V
Gate Threshold Voltage <sup>4</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.6	2.2	
Gate-Body Leakage <sup>4</sup>	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = +20V/-16V			±100	nA
Zero Gate Voltage Drain Current <sup>4</sup>	I <sub>DSS</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	86			A
Drain-Source On-State Resistance <sup>1,4</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		3.8	4.3	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A		6.0	7.0	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 5A		33		S
<b>DYNAMIC</b>						
Input Capacitance <sup>5</sup>	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz		980		pF
Output Capacitance <sup>5</sup>	C <sub>oss</sub>			352		
Reverse Transfer Capacitance <sup>5</sup>	C <sub>rss</sub>			43		
Gate Resistance <sup>4,5</sup>	R <sub>g</sub>	f = 1MHz		0.9		Ω
Total Gate Charge <sup>1,2,5</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		16		nC
	Q <sub>g</sub> (V <sub>GS</sub> =4.5V)			7.3		
Gate-Source Charge <sup>1,2,5</sup>	Q <sub>gs</sub>			3.8		
Gate-Drain Charge <sup>1,2,5</sup>	Q <sub>gd</sub>			2.5		
Turn-On Delay Time <sup>1,2,5</sup>	t <sub>d(on)</sub>			6.8		
Rise Time <sup>1,2,5</sup>	t <sub>r</sub>	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 5A, R <sub>g</sub> = 3Ω		13		
Turn-Off Delay Time <sup>1,2,5</sup>	t <sub>d(off)</sub>			16		
Fall Time <sup>1,2,5</sup>	t <sub>f</sub>			2.8		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Continuous Current	I <sub>S</sub>				42	A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				170	
Forward Voltage <sup>1,4</sup>	V <sub>SD</sub>	I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0V			1.2	V
Reverse Recovery Time <sup>5</sup>	t <sub>rr</sub>	I <sub>F</sub> = 20A, di/dt = 400A / μS		13		nS
Peak Reverse Recovery Current <sup>5</sup>	I <sub>RM(REC)</sub>			2.1		A
Reverse Recovery Charge <sup>5</sup>	Q <sub>rr</sub>				14	

<sup>1</sup>Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.

<sup>4</sup>Guarantee by FT test Item

<sup>5</sup>Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



-Q1\_TYPICAL CHARACTERISTICS

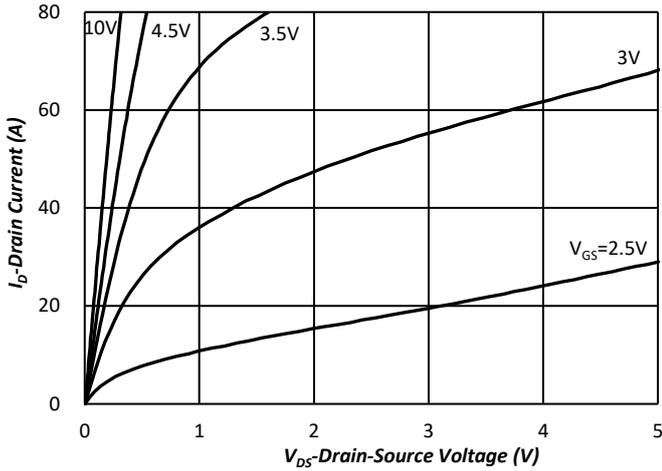


Fig.1 Typical Output Characteristics

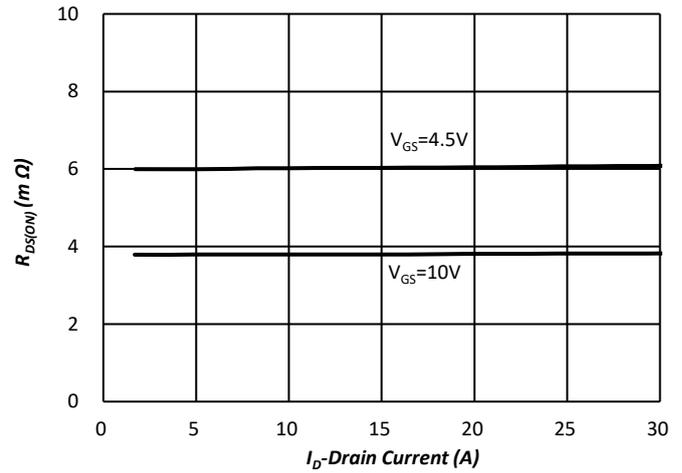


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

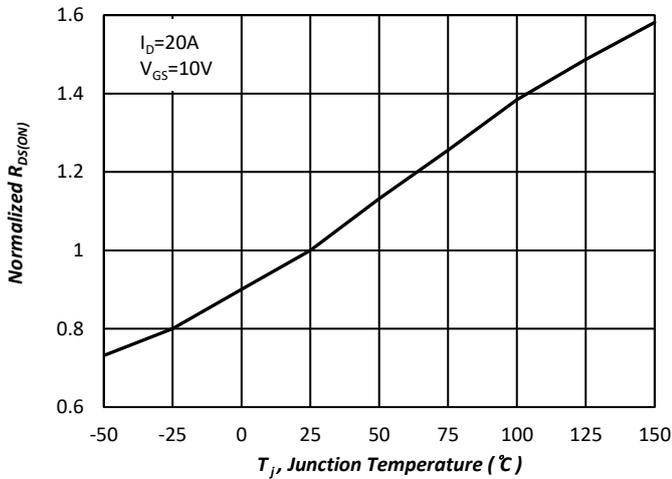


Fig.3 Normalized On-Resistance v.s. Junction Temperature

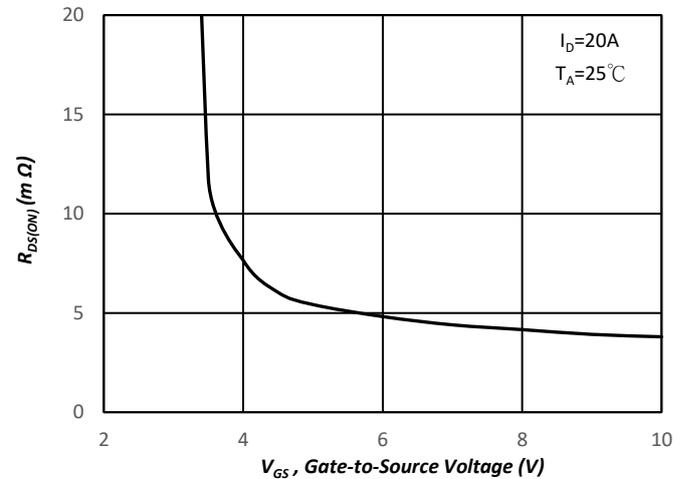


Fig.4 On-Resistance v.s. Gate Voltage

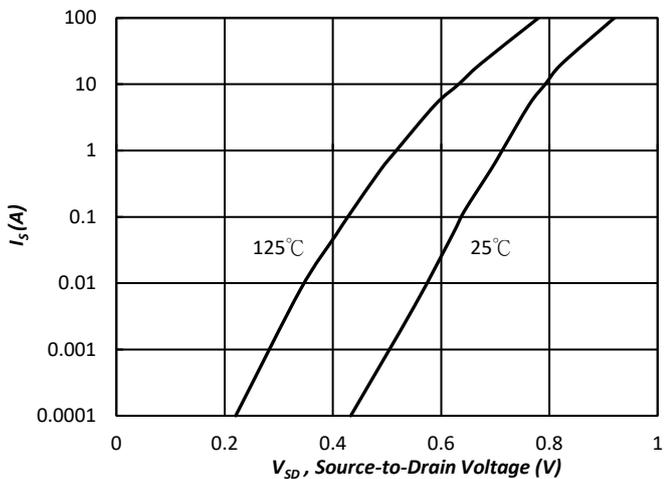


Fig.5 Forward Characteristic of Reverse Diode

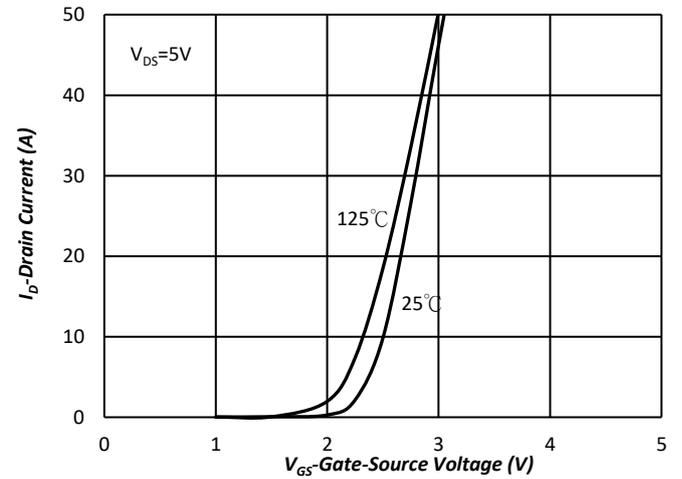
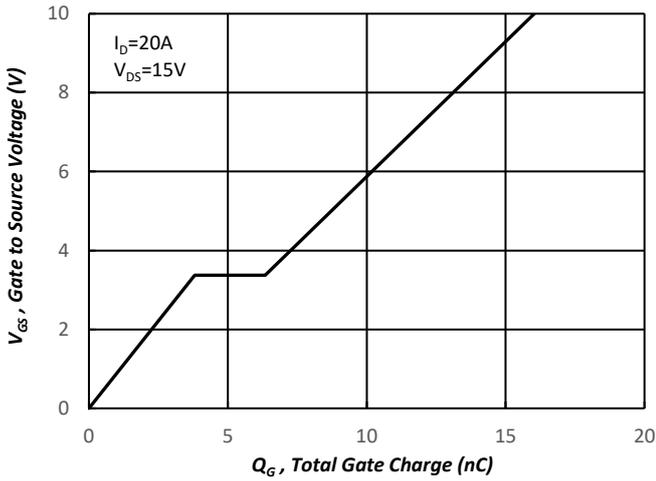
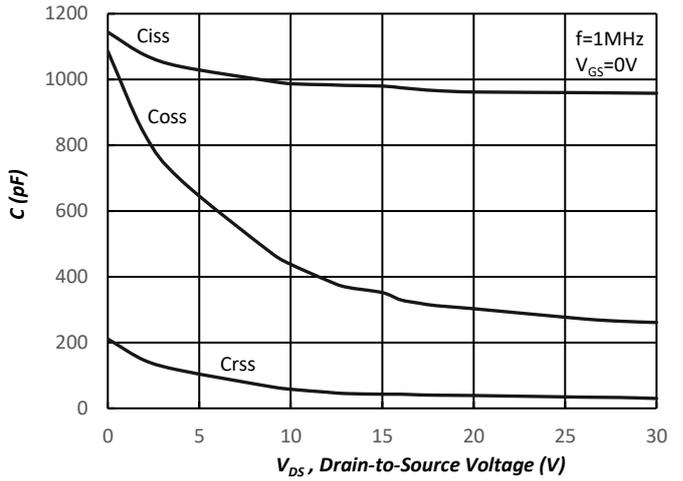


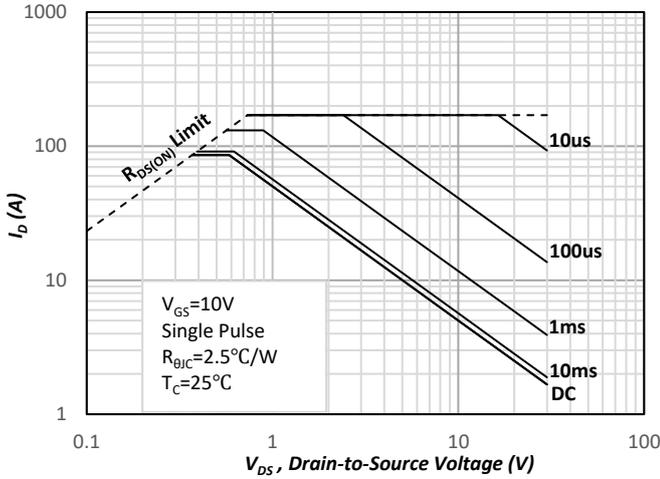
Fig.6 Transfer Characteristics



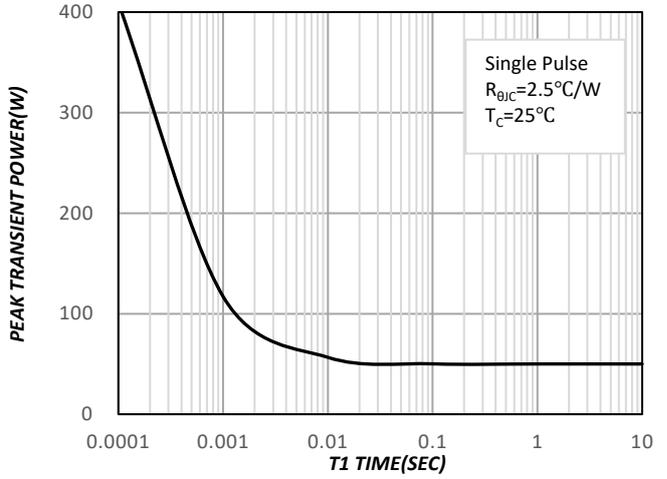
**Fig.7 Gate Charge Characteristics**



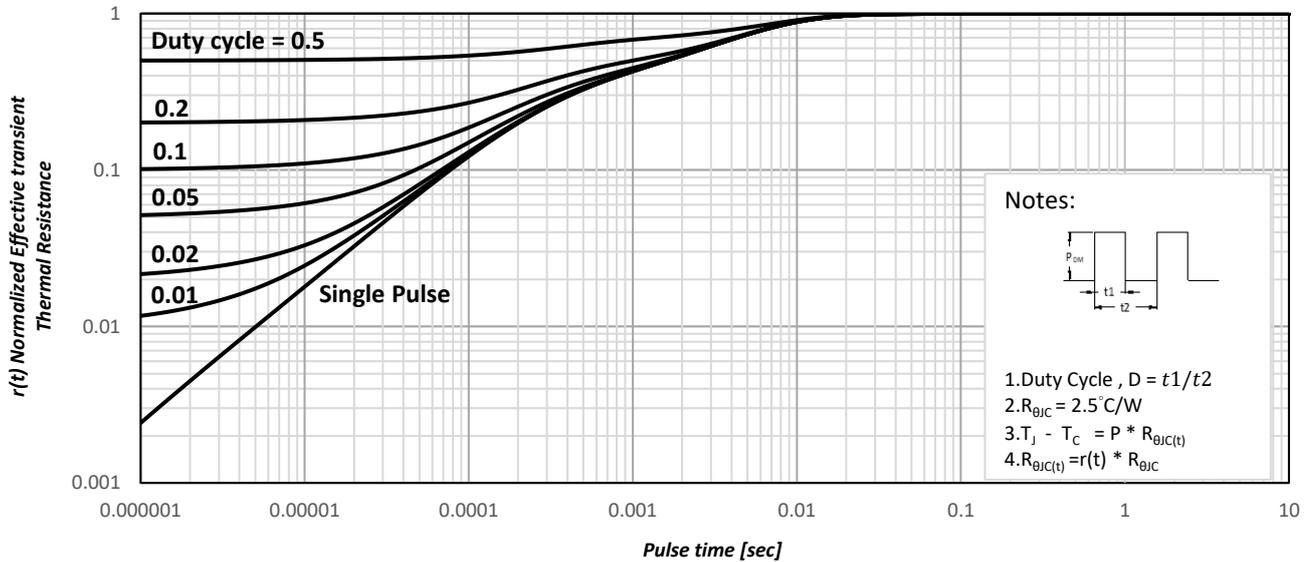
**Fig.8 Typical Capacitance Characteristics**



**Fig.9. Maximum Safe Operating Area**



**Fig.10. Single Pulse Maximum Power Dissipation**



**Fig.11. Effective Transient Thermal Impedance**



▪ Q2\_ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage <sup>4</sup>	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30			V
Gate Threshold Voltage <sup>4</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.5	2.2	
Gate-Body Leakage <sup>4</sup>	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±12V			±100	nA
Zero Gate Voltage Drain Current <sup>4</sup>	I <sub>DSS</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	240			A
Drain-Source On-State Resistance <sup>1,4</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A		0.7	0.95	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 30A		0.9	1.15	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 5A		130		S
<b>DYNAMIC</b>						
Input Capacitance <sup>5</sup>	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz		4850		pF
Output Capacitance <sup>5</sup>	C <sub>oss</sub>			1645		
Reverse Transfer Capacitance <sup>5</sup>	C <sub>rss</sub>			59		
Gate Resistance <sup>4,5</sup>	R <sub>g</sub>	f = 1MHz		0.9		Ω
Total Gate Charge <sup>1,2,5</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		72		nC
	Q <sub>g</sub> (V <sub>GS</sub> =4.5V)			31		
Gate-Source Charge <sup>1,2,5</sup>	Q <sub>gs</sub>			16		
Gate-Drain Charge <sup>1,2,5</sup>	Q <sub>gd</sub>			8.1		
Turn-On Delay Time <sup>1,2,5</sup>	t <sub>d(on)</sub>		V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 5A, R <sub>g</sub> = 3Ω		12	
Rise Time <sup>1,2,5</sup>	t <sub>r</sub>			16		
Turn-Off Delay Time <sup>1,2,5</sup>	t <sub>d(off)</sub>			53		
Fall Time <sup>1,2,5</sup>	t <sub>f</sub>			22		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Continuous Current	I <sub>S</sub>				74	A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				699	
Forward Voltage <sup>1,4</sup>	V <sub>SD</sub>	I <sub>F</sub> = I <sub>S</sub> , V <sub>GS</sub> = 0V			1.2	V
Reverse Recovery Time <sup>5</sup>	t <sub>rr</sub>	I <sub>F</sub> = 20A, di/dt = 400A / μS		41		nS
Peak Reverse Recovery Current <sup>5</sup>	I <sub>RM(REC)</sub>			4.4		A
Reverse Recovery Charge <sup>5</sup>	Q <sub>rr</sub>			99		nC

<sup>1</sup>Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

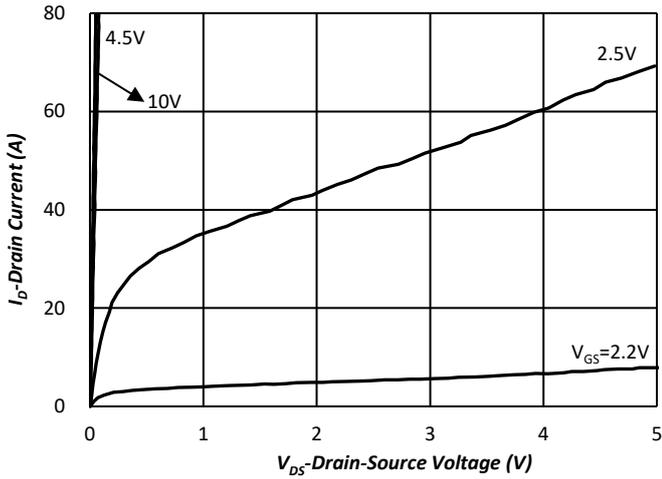
<sup>3</sup>Pulse width limited by maximum junction temperature.

<sup>4</sup>Guarantee by FT test Item

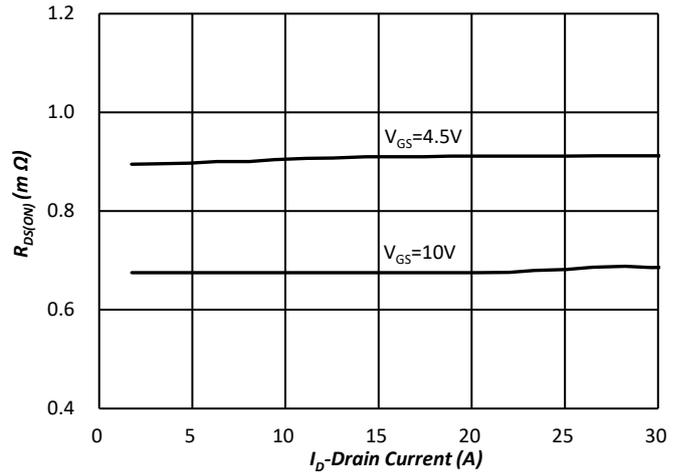
<sup>5</sup>Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.

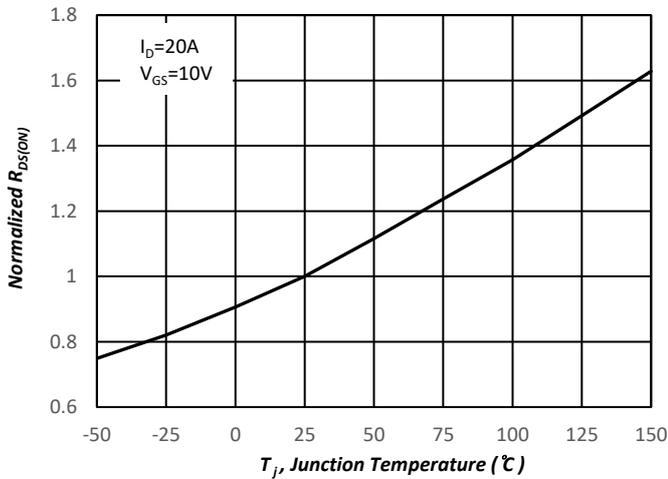
**-Q2\_TYPICAL CHARACTERISTICS**



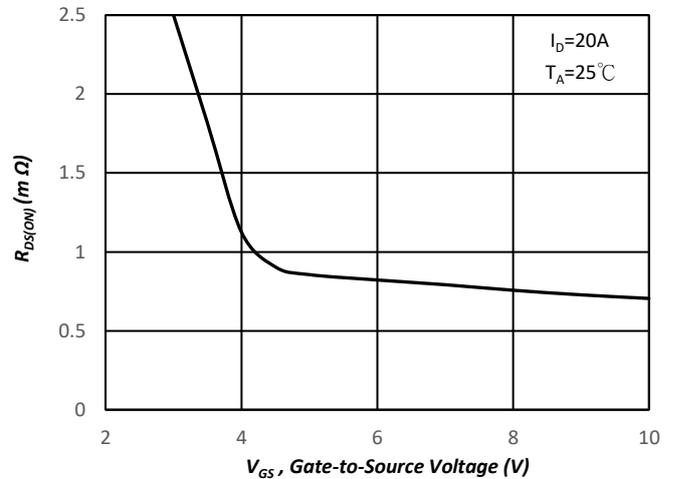
**Fig.1 Typical Output Characteristics**



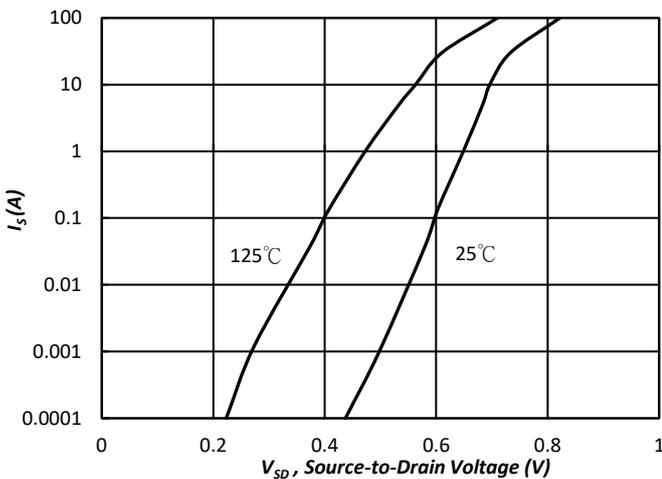
**Fig.2 On-Resistance Variation with Drain Current and Gate Voltage**



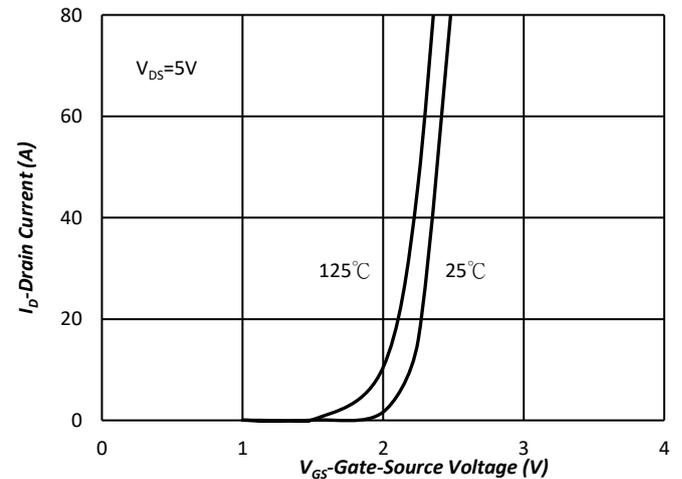
**Fig.3 Normalized On-Resistance v.s. Junction Temperature**



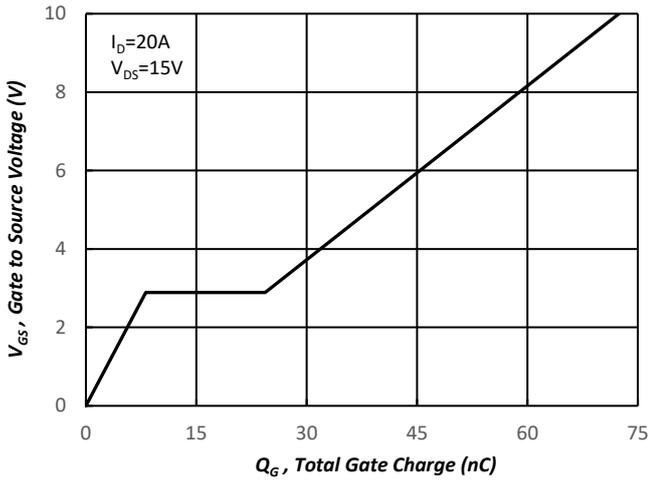
**Fig.4 On-Resistance v.s. Gate Voltage**



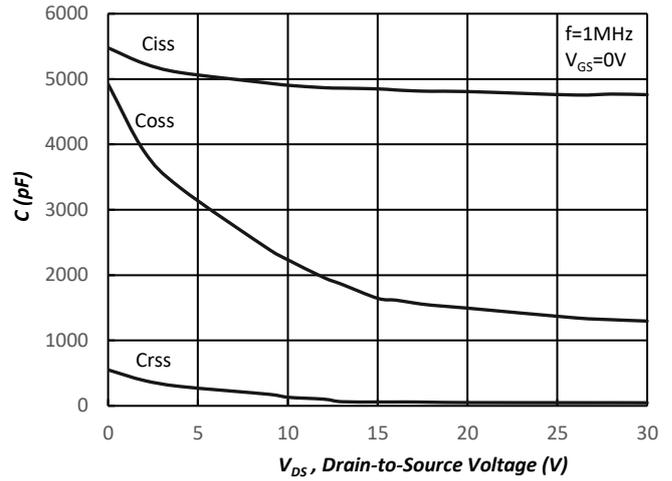
**Fig.5 Forward Characteristic of Reverse Diode**



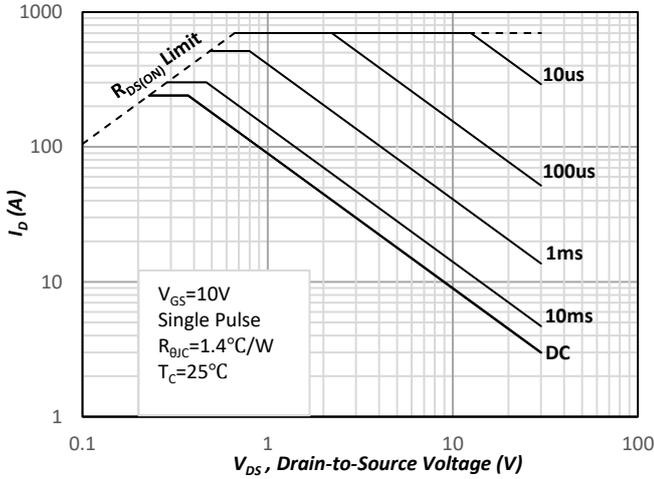
**Fig.6 Transfer Characteristics**



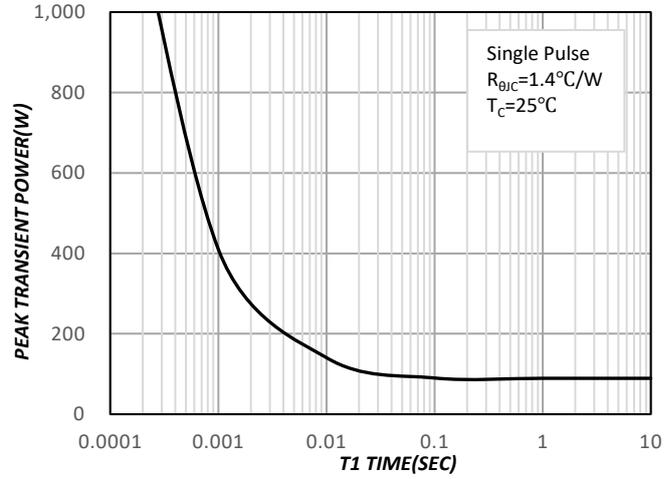
**Fig.7 Gate Charge Characteristics**



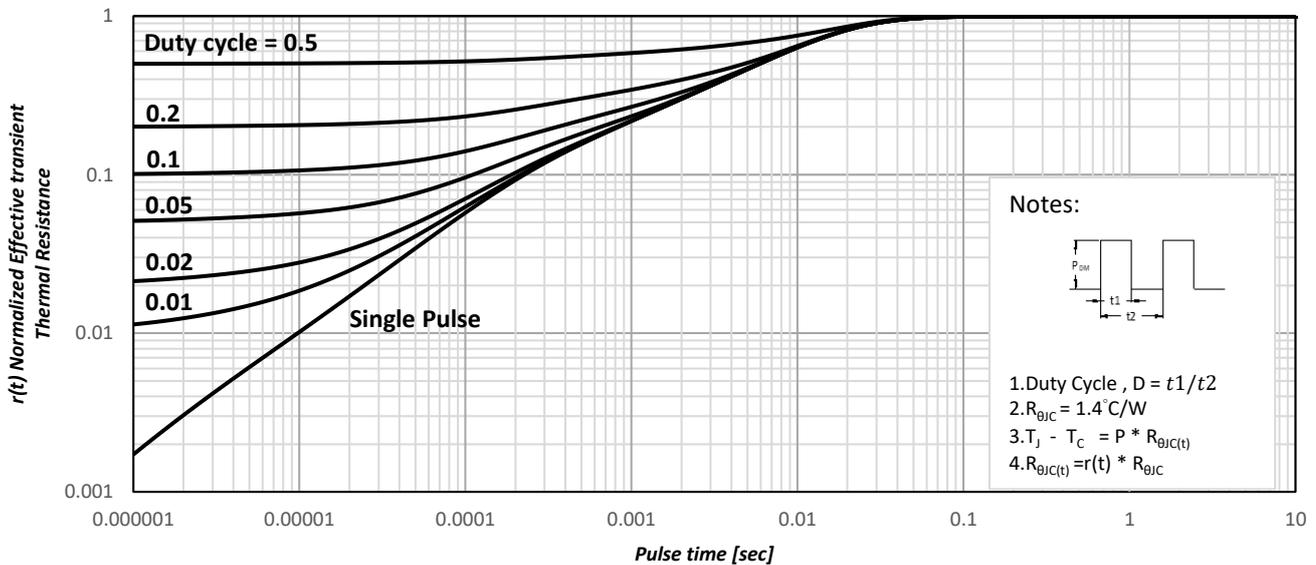
**Fig.8 Typical Capacitance Characteristics**



**Fig.9. Maximum Safe Operating Area**



**Fig.10. Single Pulse Maximum Power Dissipation**



**Fig.11. Effective Transient Thermal Impedance**

**Ordering & Marking Information:**

Device Name: EMP08Q03HTCS for DFN5X6A-8L ASYM



→ P08Q03S : Device Name

→ ABCDEFG: Date Code

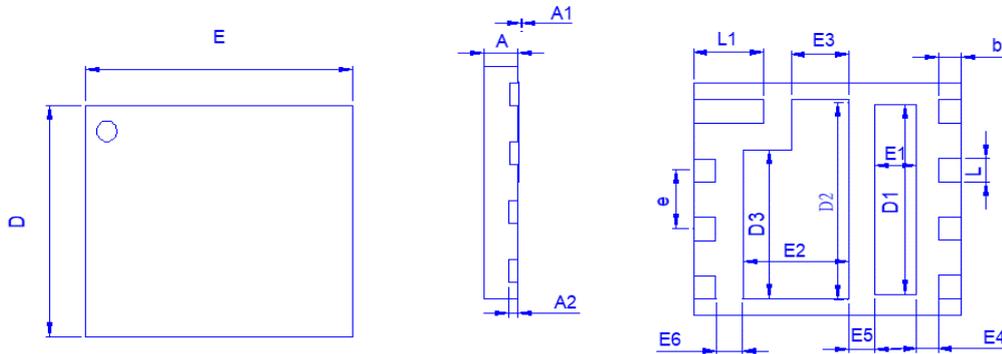
A: Assembly House

B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

DEFG: Serial No.

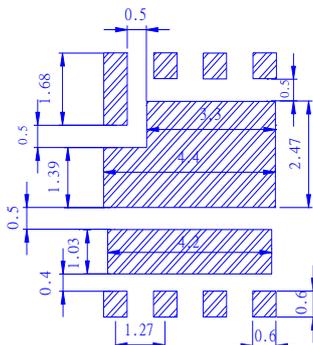
**Outline Drawing**



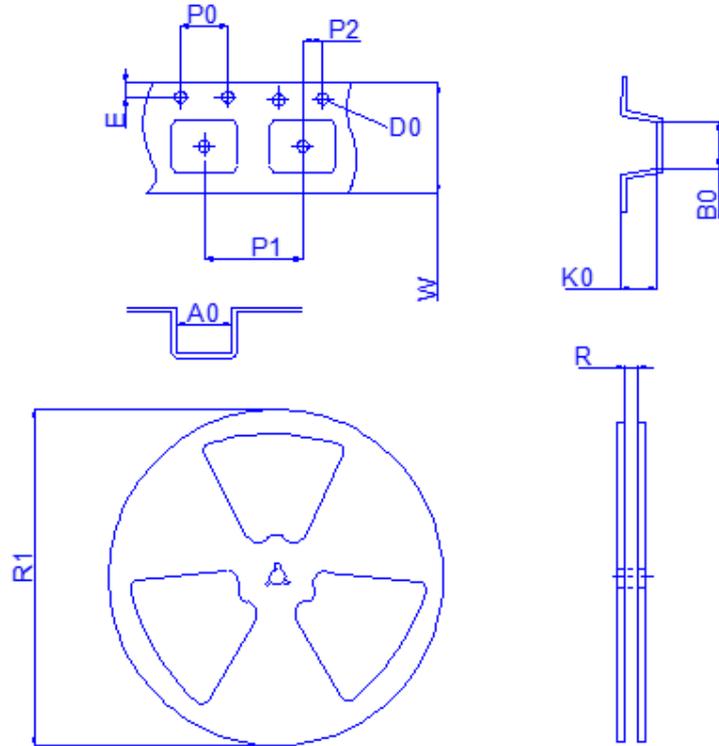
Dimension	A	A1	A2	D	E	D1	D2	D3	E1	E2	E3	E4	E5
Min.	0.70	-	-	4.90	5.90	3.85	4.17	3.10	0.83	2.27	1.20	0.40	0.48
Typ.	0.75	0.02	0.20	5.00	6.00	3.90	4.22	3.15	0.91	2.37	1.30	0.49	0.53
Max.	0.80	0.05	-	5.10	6.10	4.20	4.40	3.31	1.03	2.51	1.42	0.60	0.70

Dimension	E6	L	L1	e	b
Min	0.50	0.40	1.48	1.17	0.40
Typ.	0.60	0.48	1.57	1.27	0.50
Max	0.70	0.60	1.68	1.37	0.60

**Footprint**



◆ Tape&Reel Information:2500pcs/Reel



Package	DFN5X6A-8L
Reel	13"
Device orientation	<p>FEEED DIRECTION</p> <p>→</p>

**Dimension in mm**

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	6.4	5.3	1.5	1.8	1.6	4	8	2	12	12.4	330
±	0.2	0.2	0.1	0.1	0.6	0.1	0.1	0.1	0.3	2	2